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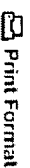
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## Full chip false timing path identification: applications to the PowerPC™ microprocessors

Jing Zeng, Abadir, M.S., Bhadra, J., Abraham, J.A.,ASP Somerset Design Center, Motorola Inc., Austin, TX;*This paper appears in: Design, Automation and Test in Europe, 2001. Conference and Exhibition 2001. Proceedings*03/13/2001-03/16/2001, 2001Location: Munich, GermanyOn page(s): 514-5182001References Cited: 11Number of Pages: xxxvi+829INSPEC Accession Number: 6964654**Abstract:**

Static timing analysis sets the industry standard in the design methodology of high speed/performance microprocessors to determine whether timing requirements have been met. Unfortunately, not all the paths identified using such analysis can be sensitized. This leads to a pessimistic estimation of the processor speed. Also, no amount of engineering effort spent on optimizing such paths can improve the timing performance of the chip. In the past we demonstrated initial results of how ATPG techniques can be used to identify false paths efficiently. Due to the gap between the physical design on which the static timing analysis of the chip is based and the test view on which the ATPG techniques are applied to identify false paths, in many cases only sections of some of the paths in the full-chip were analyzed in our initial results. In this paper, we will fully analyze all the timing paths using the ATPG techniques, thus overcoming the gap between the testing

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## Dynamical Identification Of Critical Paths For Iterative Gate Sizing

How-Rem Lin TingTing Hwang

*This paper appears in: Computer-Aided Design, 1994., IEEE/ACM International Conference on*

On page(s): 481-484

6-10 Nov 1994

ISSN: 1063-6757

**Abstract:**

Not Available

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## Intervals in software execution cost analysis

Wolf F. Ernst, R.

Inst. für Datenverarbeitungsanlagen, Tech. Univ. Braunschweig;

*This paper appears in: System Synthesis, 2000. Proceedings. The 13th International Symposium on*

09/20/2000 -09/22/2000, 2000

Location: Madrid, Spain

On page(s): 130-135

2000

References Cited: 14

IEEE Catalog Number: 00TH8500

Number of Pages: xlii+232

INSPEC Accession Number: 6748726

### Abstract:

The timing and power consumption of embedded systems are state and input data-dependent. A formal analysis of such dependencies leads to intervals rather than single values. These intervals depend on the program properties, execution paths and states of processes, as well as on the target architecture. This paper presents an approach to the analysis of process behaviour using intervals. It improves on previous work by exploiting program segments with single paths and by taking the execution context into account. The example of an ATM cell handler demonstrates significant improvements in analysis precision.

### Index Terms:

asynchronous transfer mode computer architecture embedded systems hardware-software codesign power consumption software cost estimation telecommunication computing timing ATM cell handler analysis precision embedded systems execution context execution paths input data dependence intervals power consumption process behaviour

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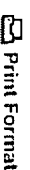
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## Primitive path delay faults: identification and their use in timing analysis

Sivaraman, M. Strojwas, A.J.

Carnegie Mellon Univ., Pittsburgh, PA;

*This paper appears in: Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on*

On page(s): 1347-1362

Volume: 19, Issue: 11, Nov 2000

ISSN: 0278-0070

References Cited: 38

CODEN: ITCSDI

INSPEC Accession Number: 6821021

### Abstract:

Present-day digital systems are characterized by large complexity, operation under tight timing constraints, numerous false paths, and large variations in component delays. In such a scenario, it is very important to ensure correct temporal behavior of these circuits, both before and after fabrication. For combinational circuits, it has been shown that it is necessary and sufficient to guarantee that the primitive path delay faults (PDFs) are fault-free to ensure that the circuit operates correctly for some timing constraint  $T$  and all larger timing constraints. We show that primitive PDFs determine the stabilization time of the circuit outputs, based on which we develop a feasible method to identify the primitive PDFs in a general multilevel logic circuit. We prove that the maximum primitive PDF delay is exactly equal to the maximum circuit delay found under the floating mode of operation assumption. From this result, we devise a method to perform timing analysis based on primitive PDF identification which delinks functional analysis from delay computation. Our timing analysis approach provides several advantages over

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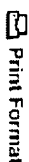
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## A quick and inexpensive method to identify false critical paths using ATPG techniques: an experiment with a PowerPC™ microprocessor

Bhadra, J. Abadir, M.S. Abraham, J.A.  
Texas Univ., Austin, TX;

*This paper appears in: Custom Integrated Circuits Conference, 2000. CICC. Proceedings of the IEEE 2000*

05/21/2000 -05/24/2000, 2000

Location: Orlando, FL, USA

On page(s): 71-74

2000

References Cited: 11

IEEE Catalog Number: 00CH37044

Number of Pages: 596

INSPEC Accession Number: 6715330

### Abstract:

Static timing analysis tools are used by designers of high speed/high performance circuits to determine whether timing requirements are met. Timing analysis tools can report critical paths which are characterized by a transition on each node along the path, however, they cannot generate a &ldquo;witness&rdquo; vector which would sensitize that path. This gives rise to the possibility of having paths which are reported by the static timing analysis tool as potential critical paths, whereas there exists no vector sequence which can sensitize them. Our goal is to identify these &ldquo>false critical timing paths&rdquo; safely and without much overhead, so that the efforts needed to redesign and/or optimize critical paths can be reduced. We have devised a simple technique using a tool that we have written

and a commercial ATPG tool to meet this goal. We applied the technique on the state of the art fourth generation MPC7400 PowerPC™ microprocessor designed at Motorola's PowerPC Design Center in Austin, TX. Our initial experimental results show the effectiveness of the technique. The salient features of the technique are that it is both quick and inexpensive.

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**Index Terms:**

automatic test pattern generation integrated circuit testing logic testing microprocessor chips timing ATPG techniques MPC7400 Motorola PowerPC microprocessor false critical paths identification

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## Full chip false timing-path identification

Jing Zeng, Abadir, M. Bhadra, J. Abraham, J.

Somerset Design Center, Motorola Inc., Austin, TX ;

*This paper appears in: **Signal Processing Systems, 2000. SIPS 2000. 2000***

### IEEE Workshop on

10/11/2000 -10/13/2000, 2000

Location: Lafayette, LA, USA

On page(s): 703-711

2000

References Cited: 11

IEEE Catalog Number: 00TH8528

Number of Pages: xv+836

INSPEC Accession Number: 6852719

### Abstract:

Static timing analysis sets the industry standard in the design methodology to gauge the speed of high performance microprocessors. Unfortunately, not all the paths identified using such analysis can be sensitized. This leads to a pessimistic estimation of processor speed, and the engineering efforts spent optimizing such paths can not improve the performance of the chip. In the past, we demonstrated initial results of how ATPG technique can be used to eliminate false paths efficiently. Due to the gap between the physical design on which the static timing analysis of the chip is based and the test view on which the ATPG technique is applied to eliminate false paths, in many cases only sections of some of the paths in the full-chip were analyzed in our initial results. In this paper, we fully analyze all the timing paths using the ATPG technique overcoming the gap between the testing and timing analysis techniques. We applied our method on the second G4 PowerPC™.



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## False timing path identification using ATPG technique and delay-based information

Jing Zeng Abadir, M. Abraham, J.

High Performance Tools &amp; Methodology, Motorola Inc., Austin, TX;

*This paper appears in: Design Automation Conference, 2002. Proceedings.***39th**

On page(s): 562-565

2002

ISSN: 0738-100X

**Abstract:**

Not Available

**Index Terms:**

automatic test pattern generation delays formal verification instruction sets integrated circuit testing logic testing microprocessor chips timing ATPG techniques Motorola MPC7455 PowerPC instruction set architecture delay information delay-based information false timing path identification processor speed static timing analysis tools timing verification total timing paths

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